

FORM PTO-1449/A and B (Modified)		APPLICATION NO.: 10/766,298	ATTY. DOCKET NO.: S1404.70004US01
INFORMATION DISCLOSURE STATEMENT BY APPLICANT		FILING DATE: January 27, 2004	CONFIRMATION NO.: Not Yet Assigned
		APPLICANT: David Spencer	
		GROUP ART UNIT: Not Yet Assigned	EXAMINER: Not Yet Assigned
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Examiner's Initials	Cite No.	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication or of issue of Cited Document MM-DD-YYYY
		Number	Kind Code		
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	A3*	4,606,760		Fritz et al.	08-09-1986
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		Office/ Country	Number	Kind Code			
/M	B1	WO	99/61671			02-12-1999	
	B2	WO	01/21317	A1		03-29-2001	
	B3	WO	02/50521	A2		06-27-2002	
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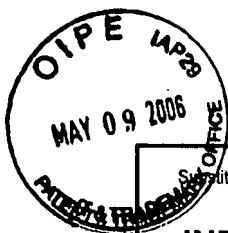
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		APPLICANT: David Spencer	
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Sheet	2	of	2

OTHER ART — NON PATENT LITERATURE DOCUMENTS

Examiner's Initials	Cite No	Include name of the author (in CAPITAL LETTERS) title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, relevant page(s), volume-issue number(s), publisher, city and/or country where published.	Translation (Y/N)
TN	C1	Yin L. et al, "A Pattern Recognition Approach in x-ray fluorescence analysis" nuclear Instruments & Methods in Physics Research, Section - A: Accelerators, Spectrometers, Detectors and Associated Equipment, NL, North-Holland Publishing Co., Amsterdam, Vol. A277, no. 2/3 + index, 1 May 1989, pgs 619-626	
	C2	Patent Abstracts of JAPAN, Vol. 1998, no. 13, 30 Nov. 1998; JP 10 216651 A (Ishikawajima Harima Heavy Ind Co. Ltd), 18 Aug 1998	
	C3	TN Spectrace, "Alloy Analyzer: Lightweight and portable, the TN Alloy Analyzer is a non-destructive, easy-to-use and accurate alloy identification and analysis tool" advertisement, 1992 (2 sheets)	
	C4	TN Technologies, "Alloy Analysis" Application Information Form, July 1997 (2 pages)	
	C5	Norman F. Johnson, "Replacing antiquated acid spot testing with a portable metal analyzer" <u>American Laboratory News Edition</u> , June 1991 (4 pages)	
	C6	TN Technologies, "The Metallurgist Pro" advertisement, 12/98 (2 pages)	
	C7	Niton Corporation, "Are you losing money selling too many loads of unsorted scrap?" flyer for the Alloy Analyzer (1 page)	
	C8	Niton Corporation, "Niton Alloy Analyzer" advertisement (2 pages)	
	C9	Arun Technology, Inc., A Roxboro Group Company, "The New Metalsort 1610" order form (1 page)	
	C10	Arun Technology, Inc., "Bangs or Bucks" mailer for the Metalscan 1650 and Metalscan 2000 (2 pages)	
	C11	TN Technologies, "Metals Sorting & Analysis" advertisement for the Metallurgist Pro (2 pages)	
	C12	TN Spectrace, "Power Solutions for Materials Analysis" booklet for Metallurgist® (8 pages)	
	C13	TN Spectrace, "Metallurgist® System Specifications," information sheet (1 page)	
	C14	Niton Corporation, "Leader in Portable XRF Technology" information booklet regarding the XL-309 Spectrum Analyzer Lead Detector and the 700 series Multi-Element Spectrum Analyzer (8 pages)	
	C15	TN Technologies, "Metallurgist Pro: Alloy Analysis and Metal Sorting" advertisement in <u>Recycling Today</u> , p. 68 November 1997 (1 page)	
	C16	Spectro Analytical Instruments, "The Profit Machine" advertisement in <u>Recycling Today</u> , p. 69, November 1997 (1 page)	
	C17	9266 Alloy Analyzer, Full Library Alloy List (Version S) Alphabetical and Table 4.2A Abbreviated Library Alloy List Alphabetical (2 pages)	
TN	C18	9277 Metallurgist-XR, Table 1A Alloy Library Categorized List (2 pages)	
EXAMINER <i>Tenn M...</i>		DATE CONSIDERED <i>8/17/07</i>	

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*a copy of this reference is not provided in accordance with the waiver notice of July 11, 2003 from the Patent and Trademark Office.



Substitute for form 1449A/B/PTO			Complete if Known		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)			Application Number	10/766298-Conf. #9344	
			Filing Date	January 27, 2004	
			First Named Inventor	Edward J. Sommer, Jr.	
			Art Unit	3654	
			Examiner Name	T. H. Matthews	
Sheet	1	of	1	Attorney Docket Number	S1404.70004US01

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		Number-Kind Code ² (if known)			
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		5,060,871	10/29/1991	Brassinga et al.	
		6,765,986	7/20/2004	Grodzins et al.	
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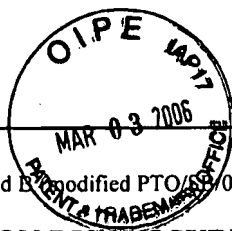
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Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				
TA		JP 08313460	11-01-1996	Shunichi et al. (English abstract)		X
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		WO 99/64853	06-12-1998	Miyamoto, et al. (English abstract)		X
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TM		WO 02/50521 A2	06-27-2002	Dalmijn, Wijnand		

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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		Appendix from U.S. Patent No. 6,801,595	
TA		"Austin AI's Automated XRF Sorting & Separating System Deemed Best Available Technology for Metals, Plastics & Glass Industries," www.austina.com , April 8, 2005.	
TA		Freifeld, K., "Art Analysis: Probing Beneath the Image," IEEE Spectrum, IEEE Inc., Jun. 1, 1986, pp. 66-71, New York.	
TA		"Research Report", Literature search of Computer and Engineering databases; Wolf, Greenfield, February 27, 2006.	

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Examiner Signature		Date Considered	8/17/07
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FORM PTO-1449/A and B (modified PTO/589/08)

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

APPLICATION NO.: 10/776,298

ATTY. DOCKET NO.: S1404.70004US01

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CONFIRMATION NO.: 9344

APPLICANT: Edward J. Sommer, et al.

GROUP ART UNIT: 3654

EXAMINER: T.H. Matthews

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of

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		Number	Kind Code		
<i>TM</i>	A23	6,765,986		Grodzins et al.	07-20-2004
<i>TM</i>	A24	6,801,595		Grodzins et al.	10-05-2004

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		Office/ Country	Number	Kind Code			
<i>TM</i>	B9	WO	02/10370		X-Ray Optical Systems, Inc.	12-27-2002	

OTHER ART — NON PATENT LITERATURE DOCUMENTS

Examiner's Initials [#]	Cite No	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation (Y/N)

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